

UNISONIC TECHNOLOGIES CO., LTD

12NM95Z **Power MOSFET**

12A, 950V N-CHANNEL SUPER-JUNCTION MOSFET

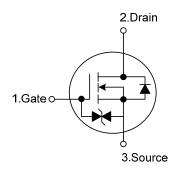
DESCRIPTION

The UTC 12NM95Z is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at AC-DC converters for power applications.

FEATURES

- * $R_{DS(ON)} \le 0.88 \Omega$ @ $V_{GS}=10V$, $I_D=4.0A$
- * High Switching Speed
- * With ESD Protected

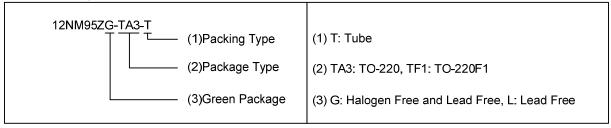
SYMBOL



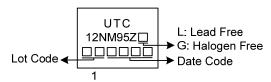
ORDERING INFORMATION

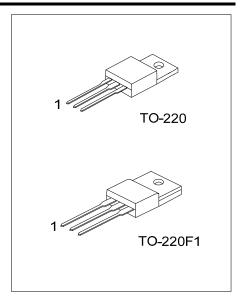
Ordering Number		Daakana	Pin Assignment			Daakina	
Lead Free	Halogen Free	Package	1	2	3	Packing	
12NM95ZL-TA3-T	12NM95ZL-TA3-T 12NM95ZG-TA3-T		G	D	S	Tube	
12NM95ZL-TF1-T 12NM95ZG-TF1-T		TO-220F1	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING





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■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		$V_{ extsf{DSS}}$	950	V	
Gate-Source Voltage		V _{GSS}	±20	V	
Drain Current	Continuous	l _D	12	А	
	Pulsed (Note 2)	I _{DM}	36	Α	
Avalanche Energy Single Pulsed (Note 3)		Eas	506	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	1.28	V/ns	
Power Dissipation	TO-220	ם	85	W	
	TO-220F1	P _D	29	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature		Tstg	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L = 100mH, I_{AS} = 3.18A, V_{DD} = 50V, R_{G} = 25 Ω Starting T_{J} = 25 $^{\circ}$ C
- 4. $I_{SD} \le 12A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT	
Junction to Ambient		θ_{JA}	62.5	°C/W	
Junction to Case	TO-220	0	1.47	°C/W	
	TO-220F1	θις	4.31	°C/W	

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

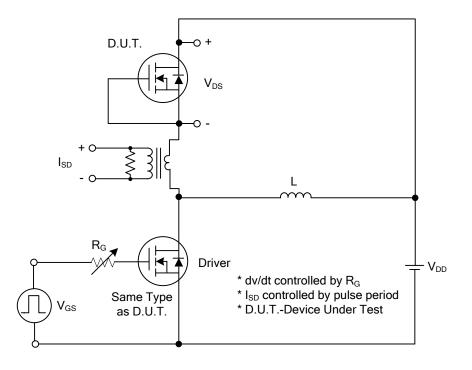
■ ELECTRICAL CHARACTERISTICS (T_J=25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage		BV_DSS	V _{GS} =0V, I _D = 250μA	950			V		
Drain-Source Leakage Current		I_{DSS}	V _{DS} =950V, V _{GS} =0V			10	μΑ		
Gate-Source Leakage Current	Forward	I _{GSS}	V_{GS} =20V, V_{DS} =0V			10	μΑ		
	Reverse		V _{GS} =-20V, V _{DS} =0V			-10	μΑ		
ON CHARACTERISTICS									
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.5		4.5	V		
Static Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =4.0A		0.715	0.88	Ω		
DYNAMIC CHARACTERISTICS									
Input Capacitance		C_ISS			1136		pF		
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =50V, f=1.0 MHz		73		pF		
Reverse Transfer Capacitance		C_{RSS}			1.8		pF		
SWITCHING CHARACTERISTICS									
Total Gate Charge (Note 1)		Q_G	\/=760\/_\/_=10\/_ =12A		38		nC		
Gate to Source Charge		Q_GS	V _{DS} =760V, V _{GS} =10V, I _D =12A (Note 1, 2)		12		nC		
Gate to Drain Charge		Q_GD	(Note 1, 2)		10		nC		
Turn-on Delay Time (Note 1)		$t_{D(ON)}$			9.6		ns		
Rise Time		t _R	V _{DS} =100V, V _{GS} =10V, I _D =12A,		17		ns		
Turn-off Delay Time		t _{D(OFF)}	R _G =25Ω (Note 1, 2)		33		ns		
Fall-Time		t _F			23		ns		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS									
Maximum Body-Diode Continuous Current		Is				12	Α		
Maximum Body-Diode Pulsed Current		I _{SM}				36	Α		
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =12A, V _{GS} =0V			1.4	V		
Reverse Recovery Time (Note 1)		t _{rr}	I _S =12A, V _{GS} =0V		490		ns		
Reverse Recovery Charge		Qrr	dl _F /dt=100A/µs (Note1)		7.4		μC		

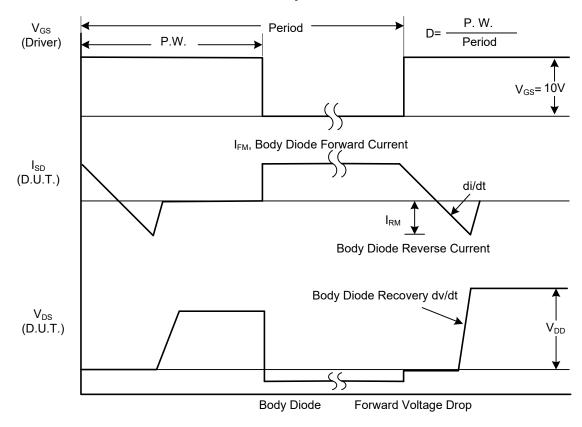
Notes: 1. Pulse Test: Pulse width \leq 300 μ s, Duty cycle \leq 2%.

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS



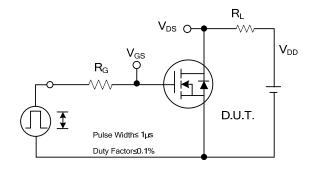
Peak Diode Recovery dv/dt Test Circuit

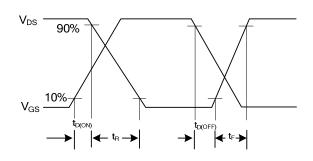


Peak Diode Recovery dv/dt Waveforms

12NM95Z Power MOSFET

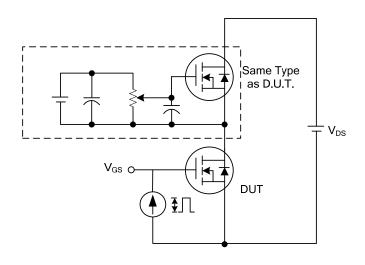
■ TEST CIRCUITS AND WAVEFORMS

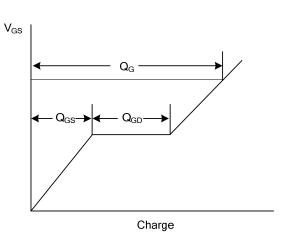




Switching Test Circuit

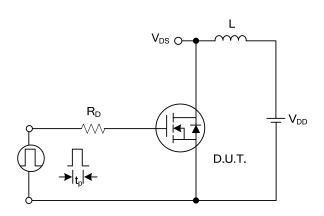
Switching Waveforms





Gate Charge Test Circuit

Gate Charge Waveform

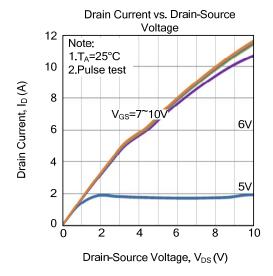


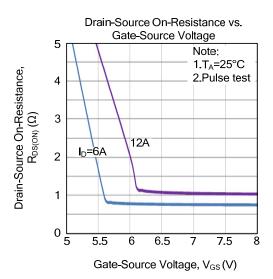
 $\begin{array}{c|c} BV_{DSS} \\ I_{AS} \\ V_{DD} \\ \hline \\ I_{D(t)} \\ \hline \\ V_{DS(t)} \\ \hline \end{array}$

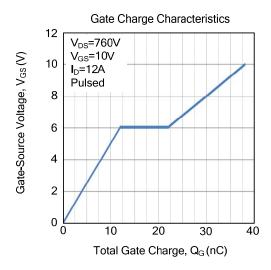
Unclamped Inductive Switching Test Circuit

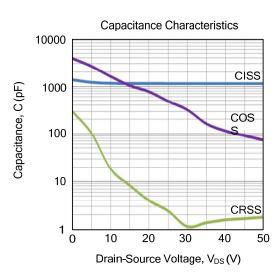
Unclamped Inductive Switching Waveforms

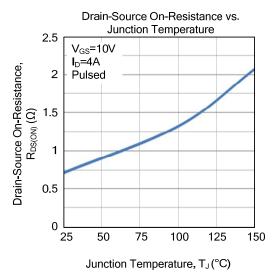
■ TYPICAL CHARACTERISTICS

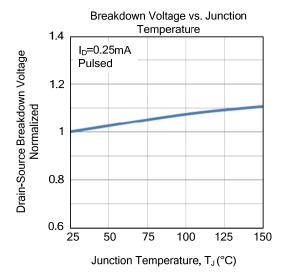




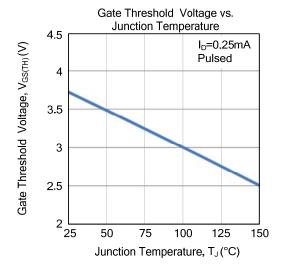


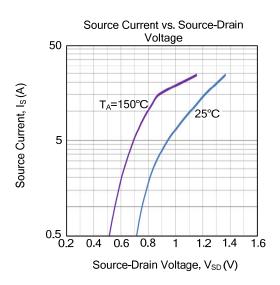


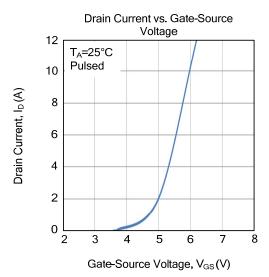


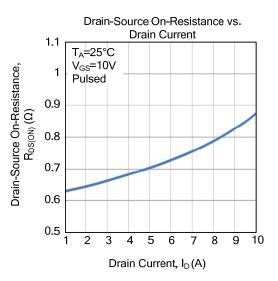


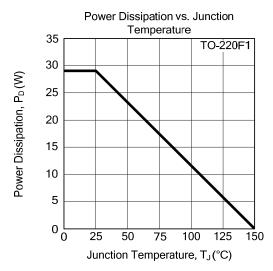
■ TYPICAL CHARACTERISTICS (Cont.)

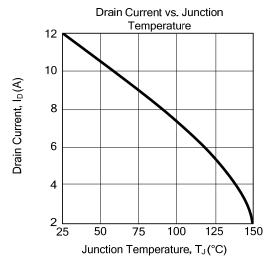




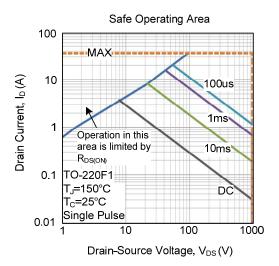








■ TYPICAL CHARACTERISTICS (Cont.)



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